

Appl. No. 09/765,958

Patent  
261/085

This listing of claims will replace all prior versions, and listings, of claims in the application.

**Listing of Claims:**

*Suit  
B3*

*A1*

1. (Original) A hierarchical test control network for an integrated circuit, comprising:  
a top-level test control circuit block, said top-level test control circuit block comprising a chip access port (CAP) controller; and  
a plurality of lower-level test control circuit blocks connected to said top-level test control circuit block in a hierarchical structure, each of said lower-level test control circuit blocks comprising a socket access port (SAP) controller;  
wherein test operation is transferred downward and upwards within said hierarchical structure.

2-14. (canceled).